



US00D450002B1

(12) **United States Design Patent**  
**Chang**

(10) **Patent No.:** **US D450,002 S**

(45) **Date of Patent:** **\*\* Nov. 6, 2001**

(54) **CLAMP TYPE ELECTRICAL MULTIMETER**

(75) Inventor: **Shang-Wen Chang, Shin-Pien (TW)**

(73) Assignee: **APPA Technology Corp., Taipei Hsien (TW)**

(\*\*) Term: **14 Years**

(21) Appl. No.: **29/135,367**

(22) Filed: **Jan. 10, 2001**

(51) **LOC (7) Cl.** ..... **10-04**

(52) **U.S. Cl.** ..... **D10/79**

(58) **Field of Search** ..... D10/79; 324/115-117,  
324/126-130, 142, 143, 149, 156, 158 P,  
158 F

(56) **References Cited**

**U.S. PATENT DOCUMENTS**

D. 422,229 \* 4/2000 Kuramoto ..... D10/79

D. 440,892 \* 4/2001 Kuramoto ..... D10/79

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*Primary Examiner*—Antoine Duval Davis  
(74) *Attorney, Agent, or Firm*—Dougherty & Troxell

(57) **CLAIM**

The ornamental design for a clamp type electrical multimeter, as shown and described.

**DESCRIPTION**

FIG. 1 is a perspective view of the clamp type electrical multimeter showing the new design;

FIG. 2 is a front view of the new design;

FIG. 3 is a rear view of the new design;

FIG. 4 is a left view of the new design;

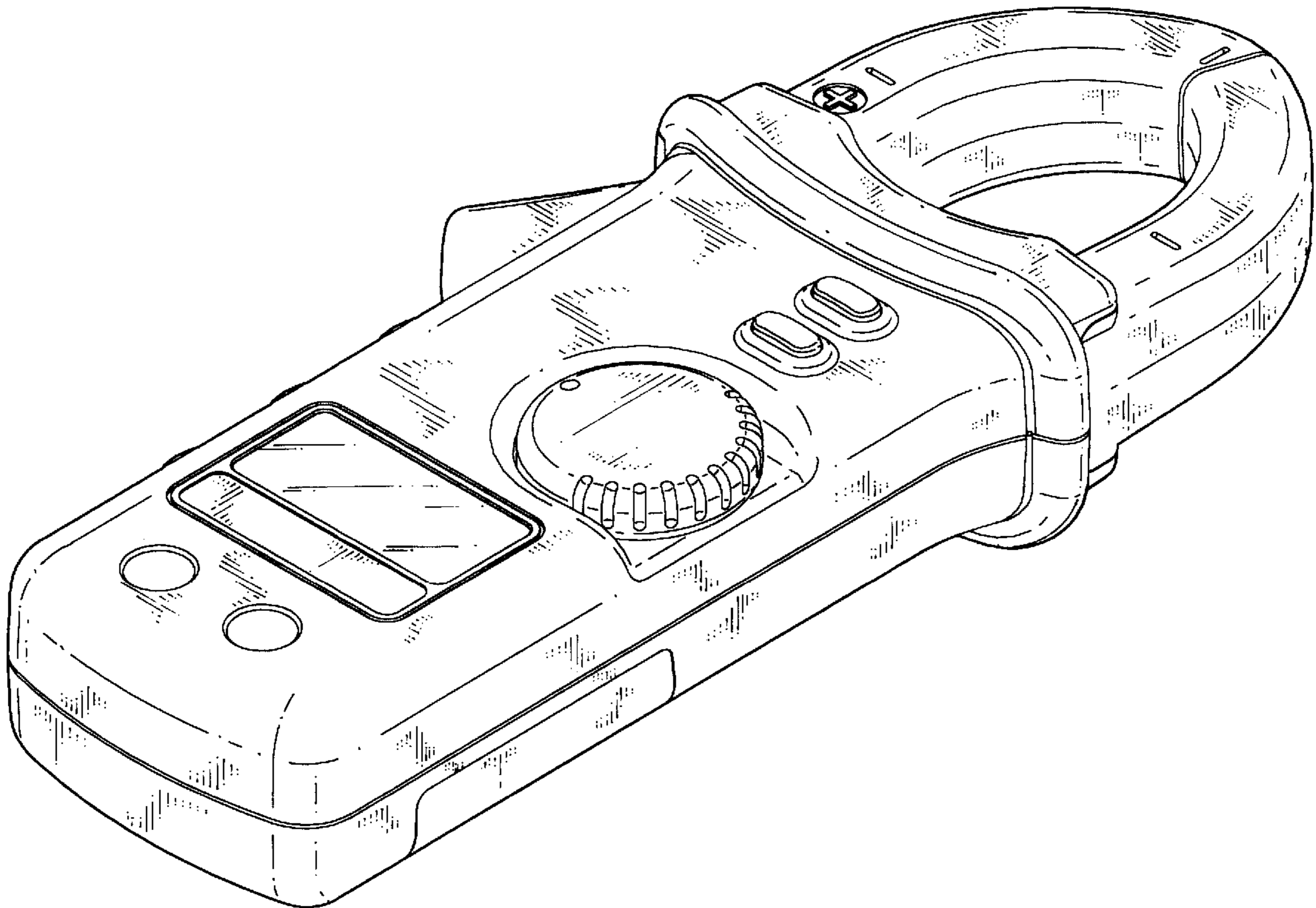
FIG. 5 is a right view of the new design;

FIG. 6 is a top view of the new design;

FIG. 7 is a bottom view of the new design; and,

FIG. 8 is a perspective view of the new design showing the status that the clamp portion is open.

**1 Claim, 7 Drawing Sheets**



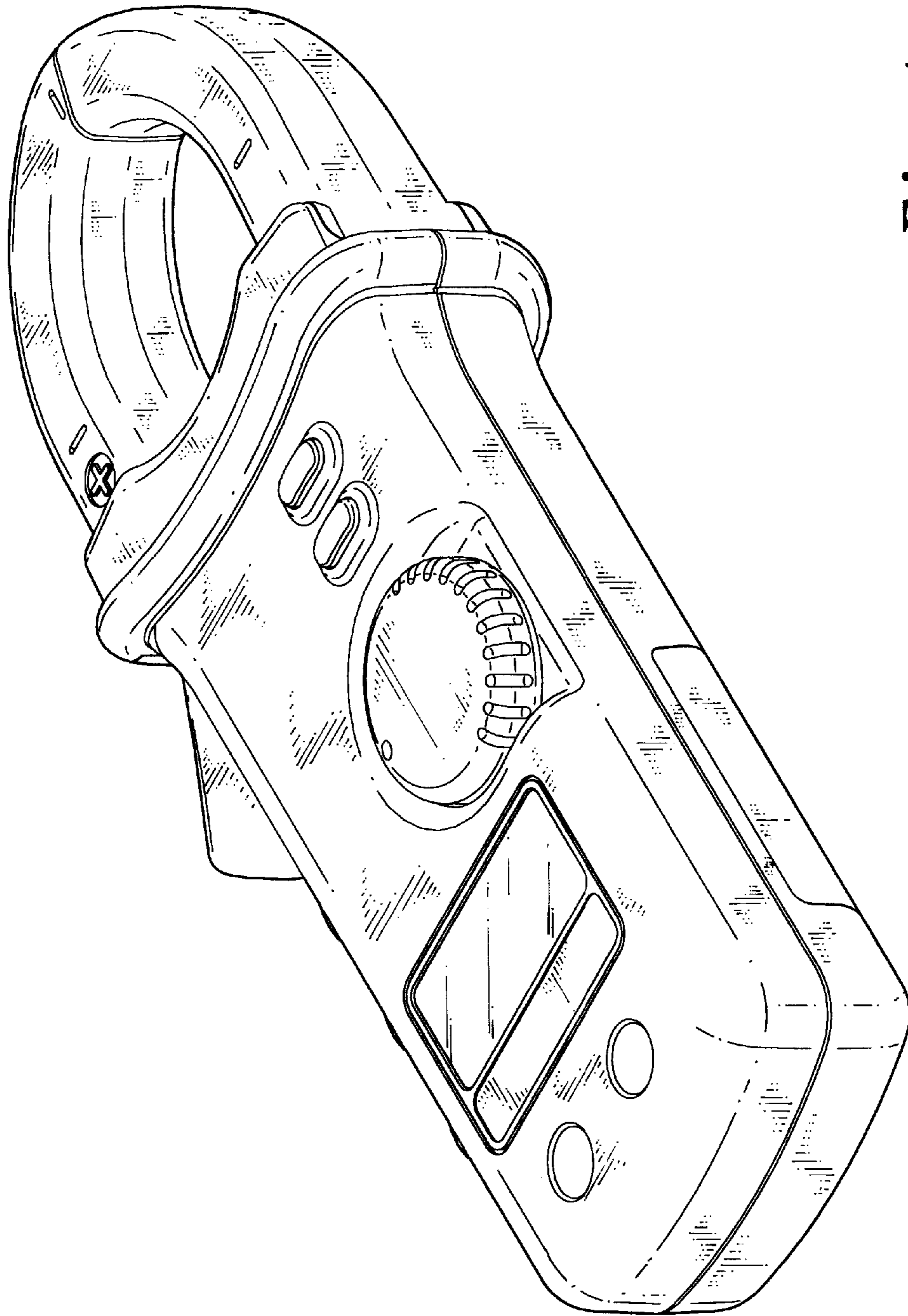


Fig. 1

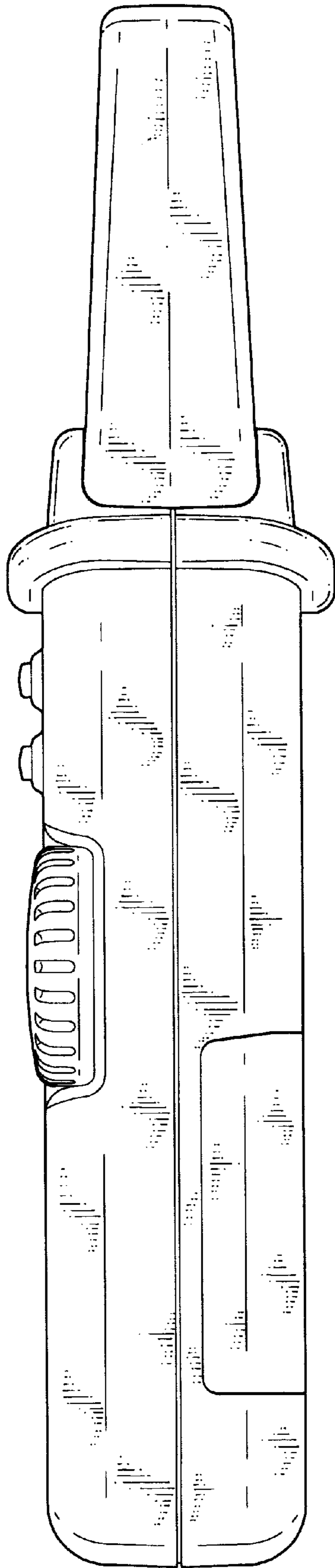


Fig. 2

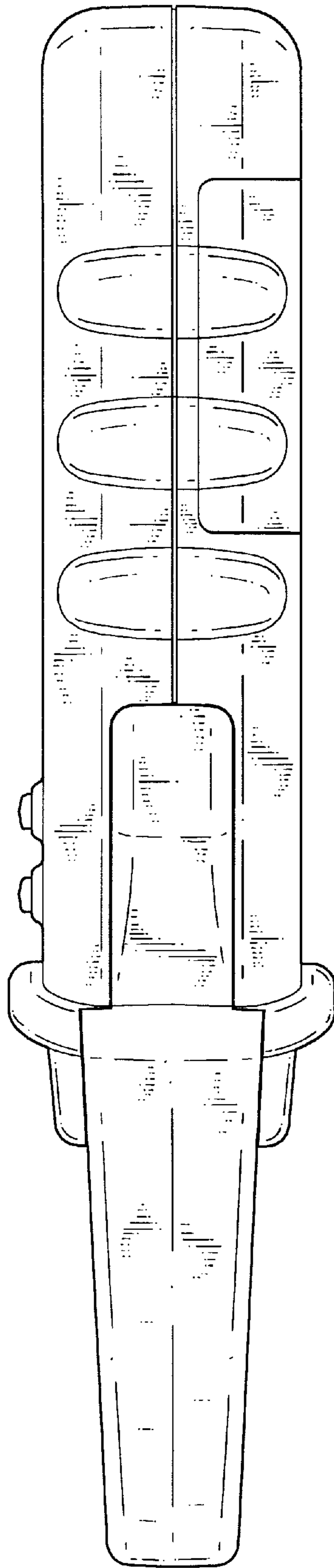


Fig. 3

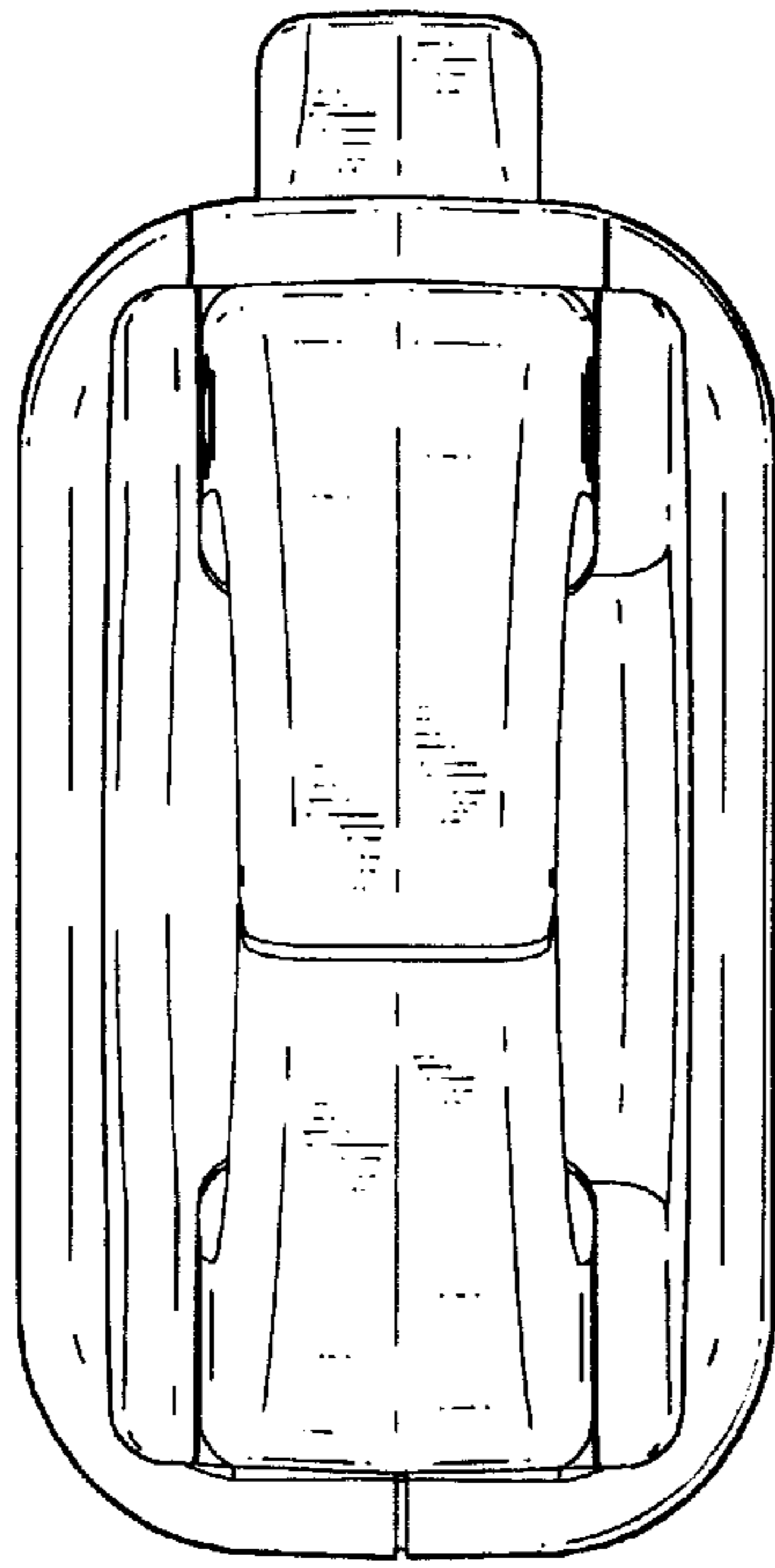


Fig. 5

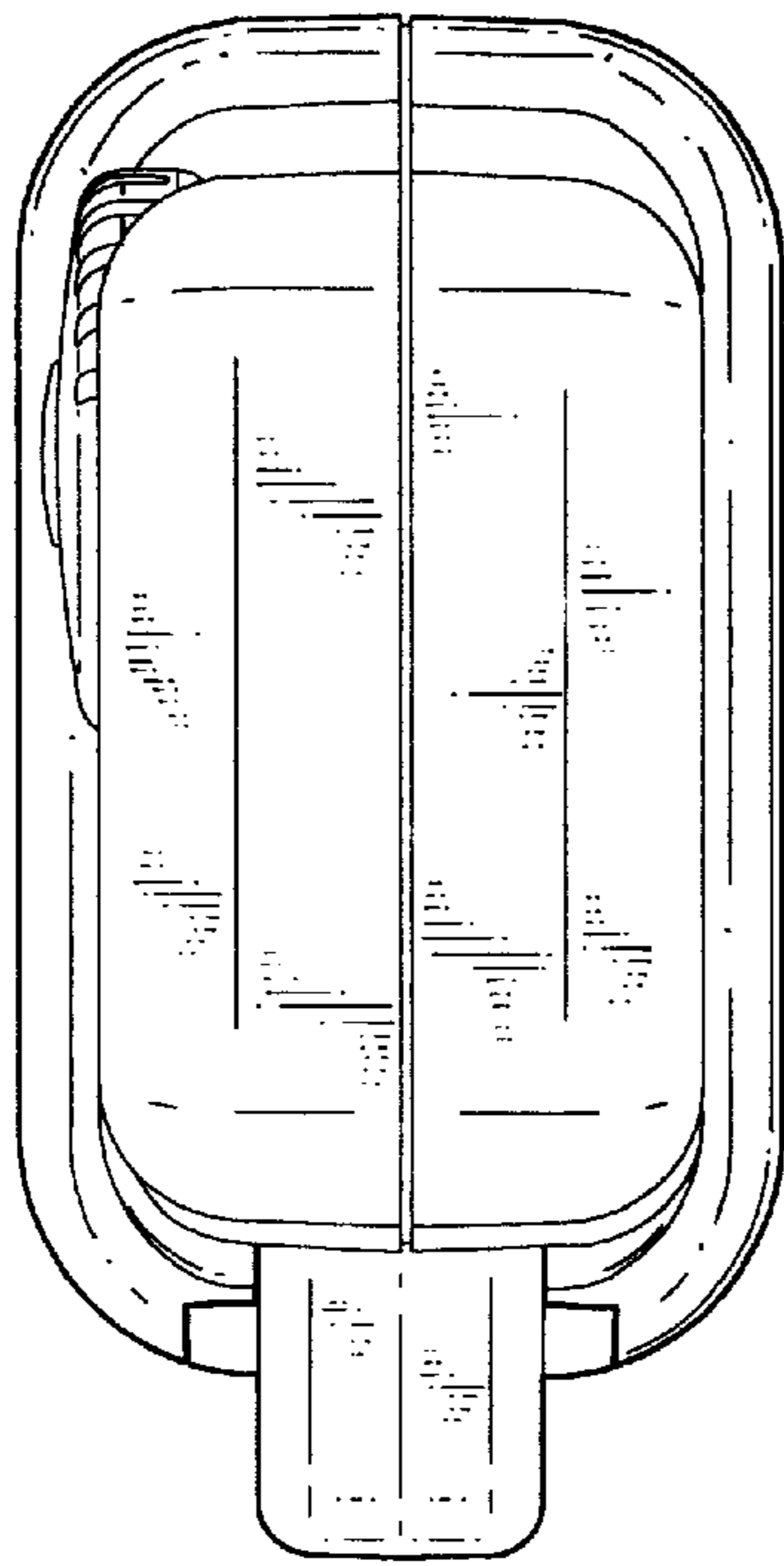


Fig. 4

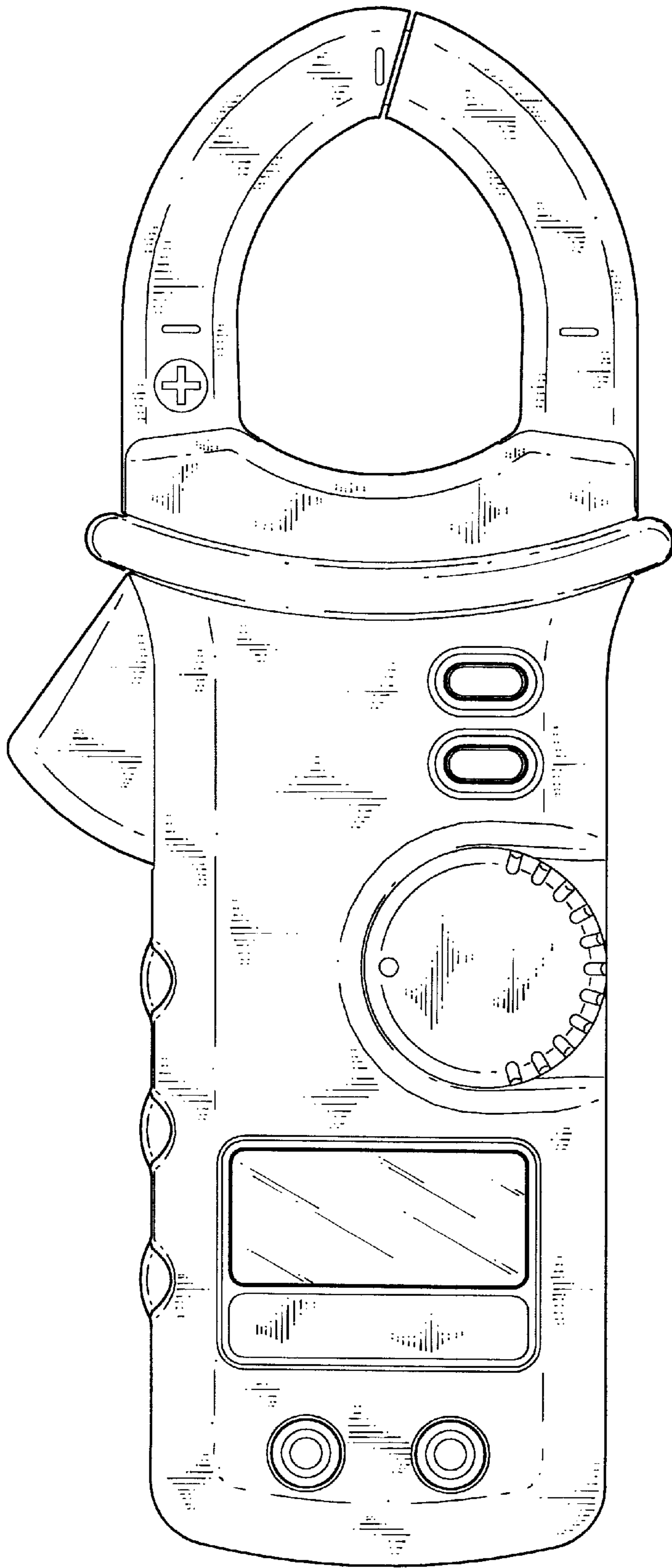


Fig. 6

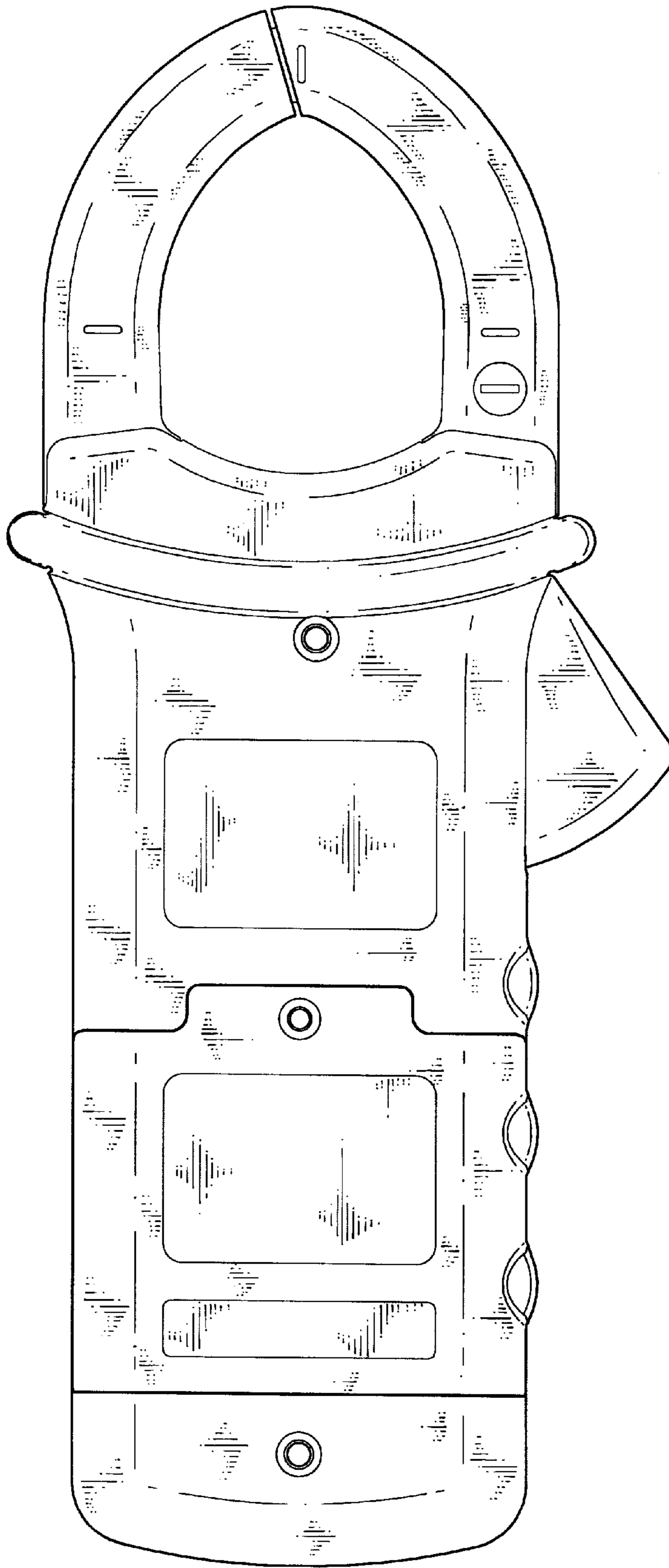


Fig. 7

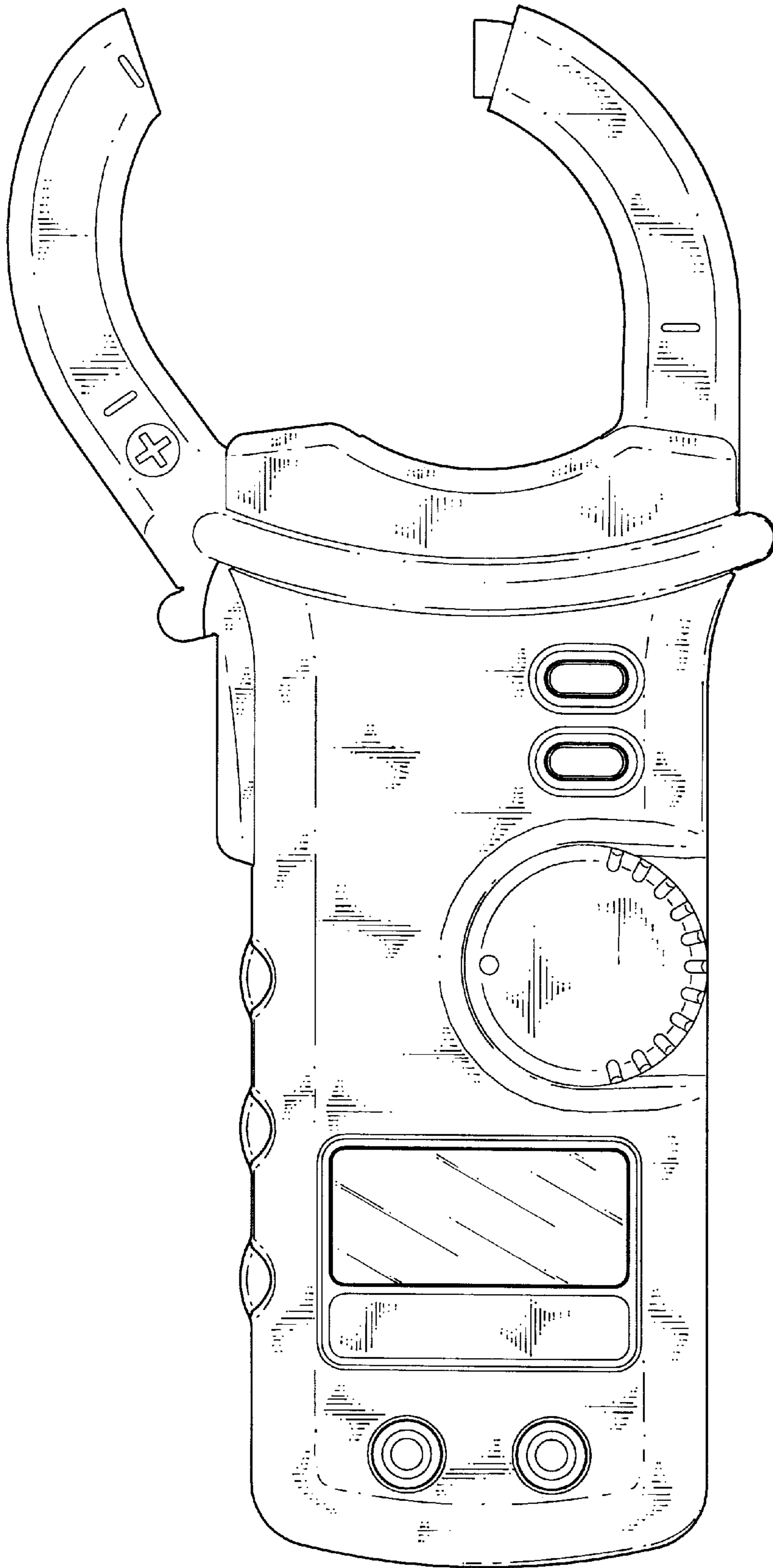


Fig. 8